

## CMOS Digital Integrated Circuits Silicon Monolithic

### Features

High speed:  $t_{pd} = 15 \text{ ns}$  (typ.) at  $V_{CC} = 5 \text{ V}$

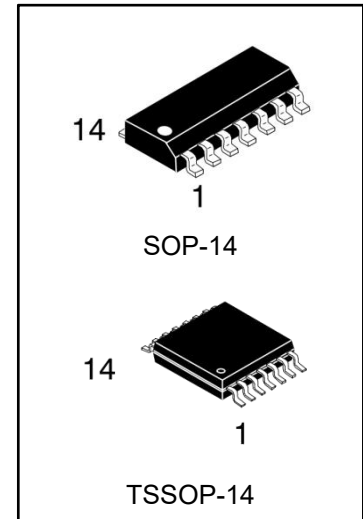
Low power dissipation:  $I_{CC} = 4.0 \mu\text{A}$  (max) at  $T_a = 25$

Balanced propagation delays:  $t_{PLH} \approx t_{PHL}$

Wide operating voltage range:  $V_{CC(\text{opr})} = 2.0 \text{ to } 6.0 \text{ V}$

### Functional Description

- 8-Channel Multiplexer



### Ordering Information

DEVICE	Package Type	MARKING	Packing	Packing Qty
74HC151DRG	SOP-14	74HC151	REEL	2500pcs/reel
74HC151PWRG	TSSOP-14	HC151	REEL	2500pcs/reel

### General Description

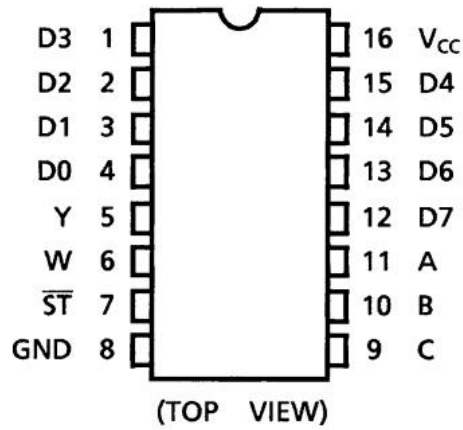
The 74HC151 is a high speed CMOS 8-CHANNEL MULTIPLEXER fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

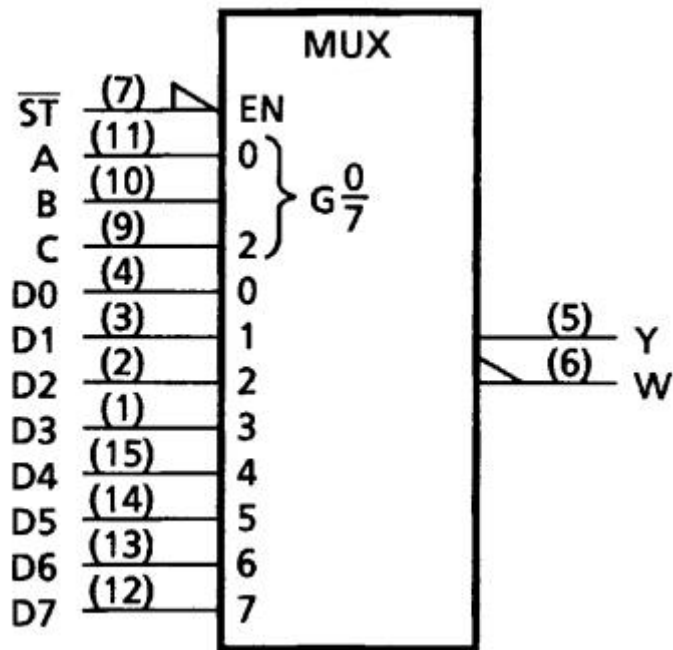
One of eight data input signals (D0-D7) is selected by decoding of the three-bit address input (A, B, C). The selected data appears on two outputs: non-inverting (Y) and inverting (W).

The strobe input provides two output conditions; a low level on the strobe input transfers the selected data to the outputs. A high level on the strobe input sets the Y output low and the W output high without regard to the data or select input conditions.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

**Pin Assignment**


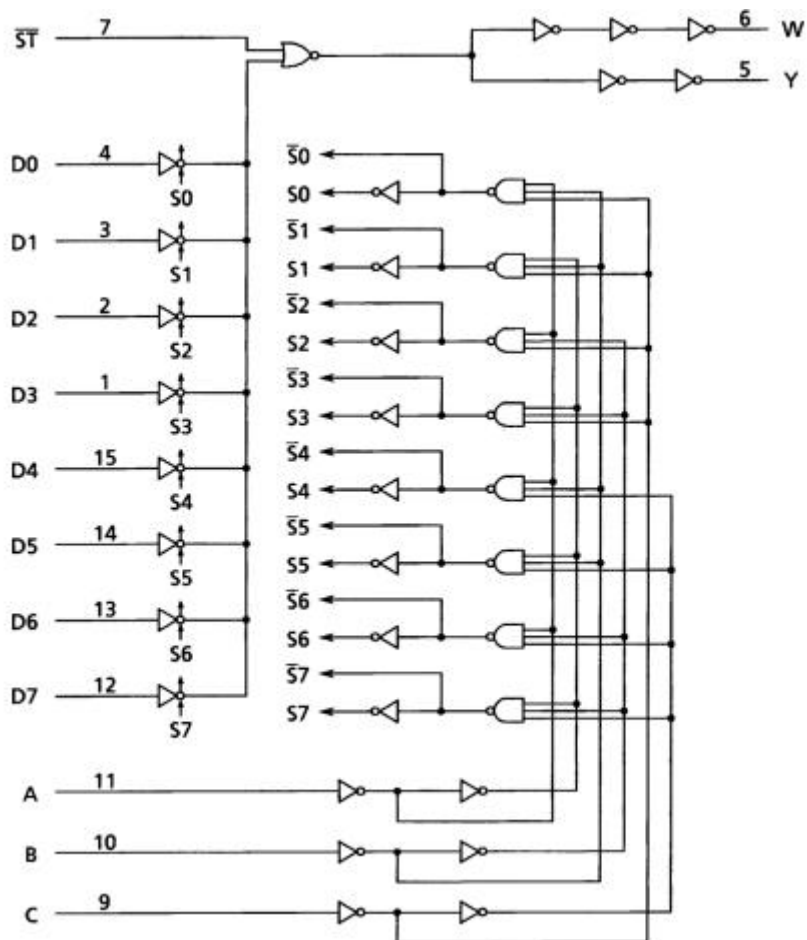
SOP-14/TSSOP-14

**IEC Logic Symbol**


**Truth Table**

Inputs				Outputs	
Select			Strobe	Y	W
C	B	A	ST		
X	X	X	H	L	H
L	L	L	L	D0	$\bar{D}0$
L	L	H	L	D1	$\bar{D}1$
L	H	L	L	D2	$\bar{D}2$
L	H	H	L	D3	$\bar{D}3$
H	L	L	L	D4	$\bar{D}4$
H	L	H	L	D5	$\bar{D}5$
H	H	L	L	D6	$\bar{D}6$
H	H	H	L	D7	$\bar{D}7$

X: Don't care

**System Diagram**


## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	$V_{CC}$		-0.5 to 7.0	V
Input voltage	$V_{IN}$		-0.5 to $V_{CC} + 0.5$	V
Output voltage	$V_{OUT}$		-0.5 to $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$		20	mA
Output diode current	$I_{OK}$		20	mA
Output current	$I_{OUT}$		25	mA
VCC/ground current	$I_{CC}$		50	mA
Power dissipation	$P_D$	(Note 1)	500	mW
Storage temperature	Tstg		-65 to 150	°C
Soldering temperature	$T_L$		245	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Note 1:  $P_D$  derates linearly with -8 mW/°C above 85

## Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	$V_{CC}$		2.0 to 6.0	V
Input voltage	$V_{IN}$		0 to $V_{CC}$	V
Output voltage	$V_{OUT}$		0 to $V_{CC}$	V
Operating temperature	$T_{opr}$		-40 to 85	°C
Input rise and fall times	$t_r, t_f$		0 to 50	µs

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.

## Electrical Characteristics

DC Characteristics (Unless otherwise specified,  $T_a = 25^\circ\text{C}$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Typ.	Max	Unit	
High-level input voltage	V <sub>IH</sub>		2.0	1.50			V	
			4.5	3.15				
			6.0	4.20				
Low-level input voltage	V <sub>IL</sub>		2.0			0.50	V	
			4.5			1.35		
			6.0			1.80		
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20μA	2.0	1.9	2.0	V	
				4.5	4.4	4.5		
			I <sub>OH</sub> = -4 mA	4.5	4.18	4.31		
				6.0	5.68	5.80		
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20μA	2.0		0.0	0.1	V
				4.5		0.0	0.1	
			I <sub>OL</sub> = 4 mA	4.5		0.17	0.26	
				6.0		0.18	0.26	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0			±0.1	μA	
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0			4.0	μA	

DC Characteristics (Unless otherwise specified,  $T_a = -40$  to  $85^\circ\text{C}$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit	
High-level input voltage	V <sub>IH</sub>		2.0	1.50		V	
			4.5	3.15			
			6.0	4.20			
Low-level input voltage	V <sub>IL</sub>		2.0		0.50	V	
			4.5		1.35		
			6.0		1.80		
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20μA	2.0	1.9		V
				4.5	4.4		
			I <sub>OH</sub> = -4 mA	4.5	4.13		
				6.0	5.63		
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20μA	2.0		0.1	V
				4.5		0.1	
			I <sub>OL</sub> = 4 mA	4.5		0.33	
				6.0		0.33	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0			±1.0	μA
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	6.0			40.0	μA

## AC Characteristics

(Unless otherwise specified,  $C_L = 15 \text{ pF}$ ,  $V_{CC} = 5 \text{ V}$ ,  $T_a = 25^\circ\text{C}$ , Input:  $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$			4	8	ns
Propagation delay time (D-Y)	$t_{PLH}, t_{PHL}$			15	24	ns
Propagation delay time (D-W)	$t_{PLH}, t_{PHL}$			15	24	ns
Propagation delay time (ST-Y)	$t_{PLH}, t_{PHL}$			10	17	ns
Propagation delay time (ST-W)	$t_{PLH}, t_{PHL}$			10	17	ns
Propagation delay time (A, B, C-Y)	$t_{PLH}, t_{PHL}$			19	31	ns
Propagation delay time (A, B, C-W)	$t_{PLH}, t_{PHL}$			19	31	ns

## AC Characteristics

(Unless otherwise specified,  $C_L = 50 \text{ pF}$ ,  $T_a = 25^\circ\text{C}$ , Input:  $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Note	$V_{CC} \text{ (V)}$	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$		2.0		30	75	ns
			4.5		8	15	
			6.0		7	13	
Propagation delay time (D-Y)	$t_{PLH}, t_{PHL}$		2.0		65	140	ns
			4.5		18	28	
			6.0		15	24	
Propagation delay time (D-W)	$t_{PLH}, t_{PHL}$		2.0		65	140	ns
			4.5		18	28	
			6.0		15	24	
Propagation delay time (ST-Y)	$t_{PLH}, t_{PHL}$		2.0		36	100	ns
			4.5		12	20	
			6.0		10	17	
Propagation delay time (ST-W)	$t_{PLH}, t_{PHL}$		2.0		36	100	ns
			4.5		12	20	
			6.0		10	17	
Propagation delay time (A, B, C-Y)	$t_{PLH}, t_{PHL}$		2.0		80	180	ns
			4.5		23	36	
			6.0		19	31	
Propagation delay time (A, B, C-W)	$t_{PLH}, t_{PHL}$		2.0		80	180	ns
			4.5		23	36	
			6.0		19	31	
Input capacitance	$C_{IN}$				3	pF	
Power dissipation capacitance	$C_{PD}$	(Note 1)			15	pF	

Note 1:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

$$I_{CC(oper)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}$$

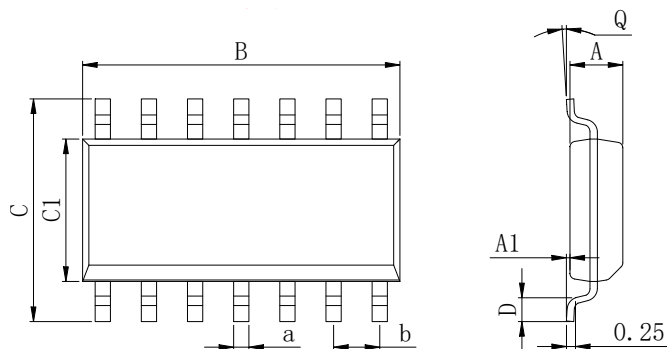
**AC Characteristics**

 (Unless otherwise specified,  $C_L = 50 \text{ pF}$ ,  $T_a = -40 \text{ to } 85^\circ\text{C}$ , Input:  $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	$V_{CC}$ (V)	Min	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$	2.0		95	ns
		4.5		19	
		6.0		16	
Propagation delay time (D-Y)	$t_{PLH}, t_{PHL}$	2.0		175	ns
		4.5		35	
		6.0		30	
Propagation delay time (D-W)	$t_{PLH}, t_{PHL}$	2.0		175	ns
		4.5		35	
		6.0		30	
Propagation delay time (ST-Y)	$t_{PLH}, t_{PHL}$	2.0		125	ns
		4.5		25	
		6.0		21	
Propagation delay time (ST-W)	$t_{PLH}, t_{PHL}$	2.0		125	ns
		4.5		25	
		6.0		21	
Propagation delay time (A, B, C-Y)	$t_{PLH}, t_{PHL}$	2.0		225	ns
		4.5		45	
		6.0		38	
Propagation delay time (A, B, C-W)	$t_{PLH}, t_{PHL}$	2.0		225	ns
		4.5		45	
		6.0		38	

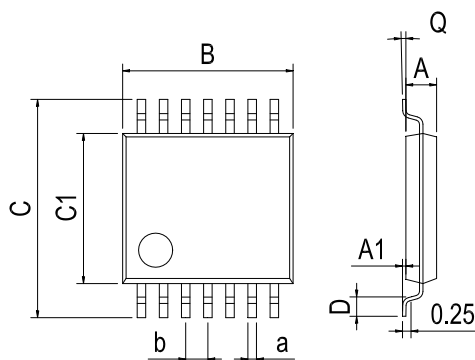
## Physical Dimensions

### SOP-14



Dimensions In Millimeters(SOP14)									
Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	1.35	0.05	8.55	5.80	3.80	0.40	0°	0.35	1.27 BSC
Max:	1.55	0.20	8.75	6.20	4.00	0.80	8°	0.45	

### TSSOP-14



Dimensions In Millimeters(TSSOP14)									
Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	0.85	0.05	4.90	6.20	4.30	0.40	0°	0.20	0.65 BSC
Max:	0.95	0.20	5.10	6.60	4.50	0.80	8°	0.25	



## Revision History

DATE	REVISION	PAGE
2014-6-8	New	1-10
2023-7-22	Update encapsulation type、 Update Soldering temperature	1、 4

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